canSAS-VIII, Apr. 14-16, J-PARC, Tokai, Japan

Applications of McSAS: software for the retrieval of parameter distributions from small-angle scattering patterns

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Small-angle scattering can do what electron microscopy never could: provide nanostructural details for vast amounts of material with little fuss. However, data correction and analysis has remained complicated.

We are, therefore, developing a comprehensive data correction methodology [1] and Monte Carlo data analysis method for unbiased nanostructural information retrieval [2]. Some of the results of the Monte Carlo method applied to practical samples are shown in this poster [3-9].

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